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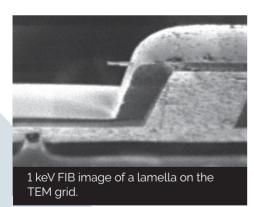
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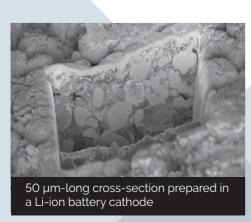
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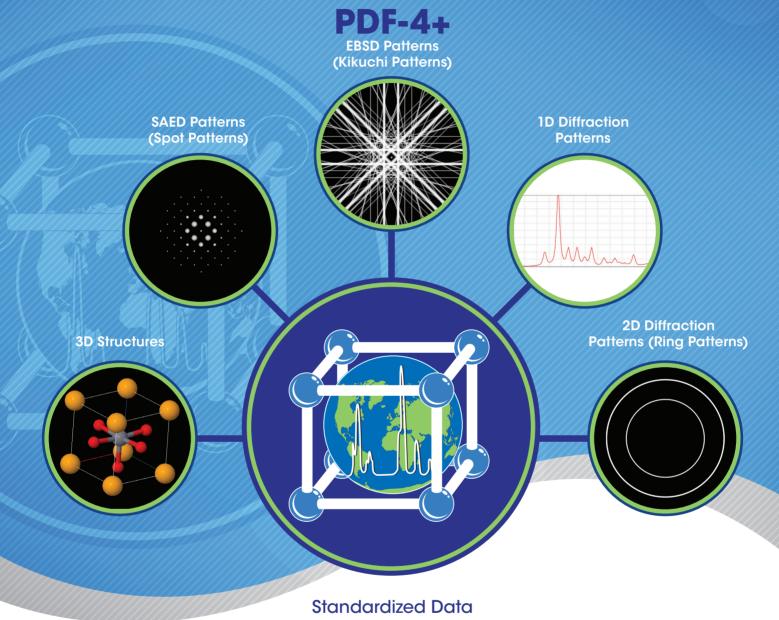
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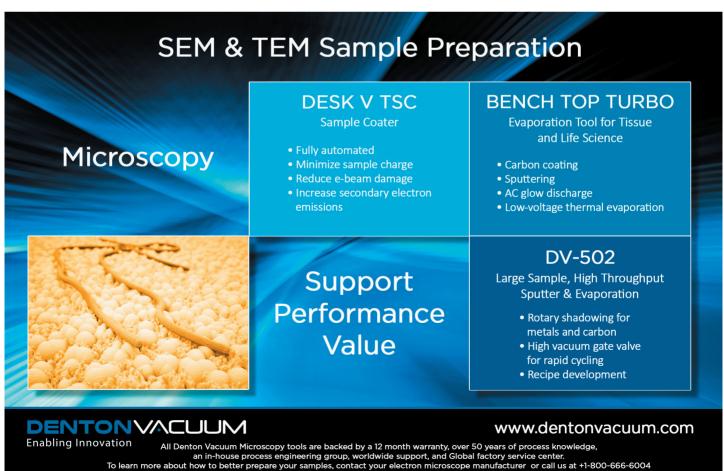
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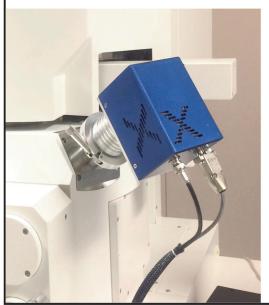






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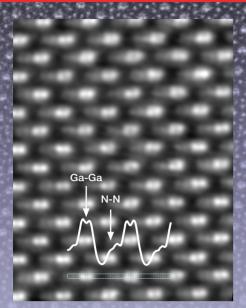
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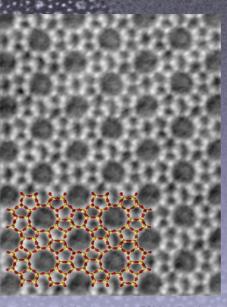
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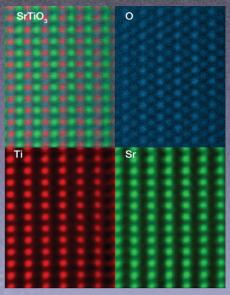
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iDPC image showing simultaneous 63 pm splitting of Ga-Ga and N-N columns in GaN [211].



Atomic resolution image of ZSM-5 Zeolite showing the complicated arrangement of the Si (yellow) and O (red) atoms in the structure (1). 1. J. Su et al, Microporous and Mesoporous Materials 189 (2014) 115–125.



Atomic resolution EDS Mapping of [110] oriented SrTiO₃ at 200kV using the Thermo Scientific™ Dual-X detector configuration.

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CONGRATULATIONS TO THE 2017 DIATOME POSTER AWARD WINNERS

DIATOME hosts a poster contest each year during Microscopy & Microanalysis annual meeting where members of the MSA council select the best poster presentation using Diamond Knives. DIATOME is proud to announce the following award winners for the 2017 meeting.

2nd PLACE WINNER (A finely sculptured Swiss Watch): Melainia McClain

Poster: Rapid Automated en Bloc Staining for SEM of Sections

3rd PLACE WINNER (A finely sculptured Swiss Watch): Sz-Chian Liou

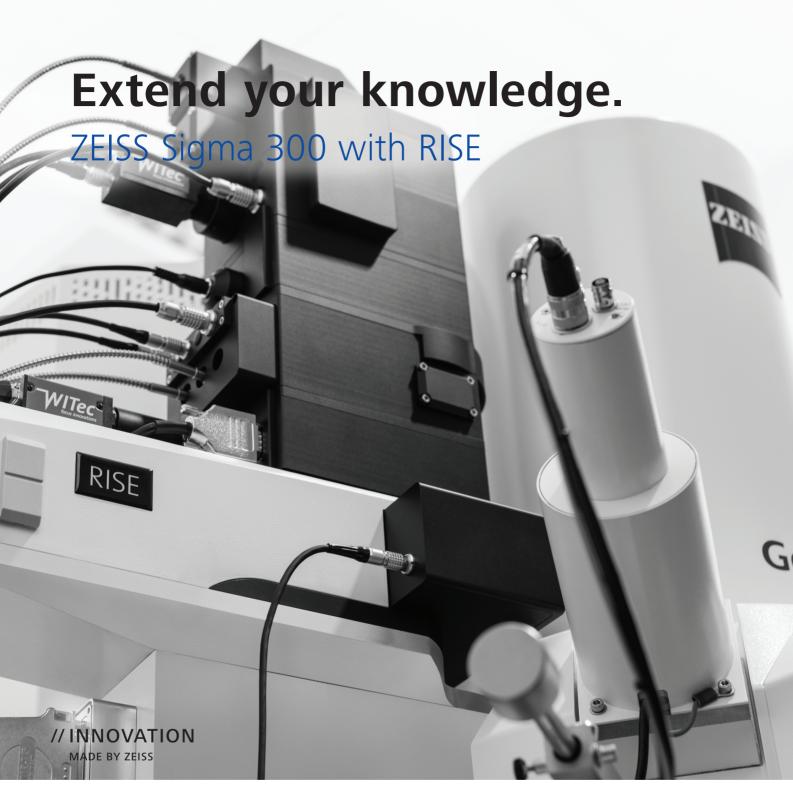
Poster: A Novel Approach in Sample Preparation of Li Content Materials for TEM Research

ELECTRON MICROSCOPY SCIENCES also gave away three free classes at the new EMS Academy to the following winners:

Melainia McClain, Stowers Institute for Medical Research Marcia M. Miller, Ph.D, City of Hope, Beckman Research Institute Bobbie L. Schneider, B.A., Fred Hutchison Cancer Research Center

A heartfelt Congratulations is extended from DIATOME and EMS to the Winners.

Sincerely yours, Stacie Kirsch, Managing Director

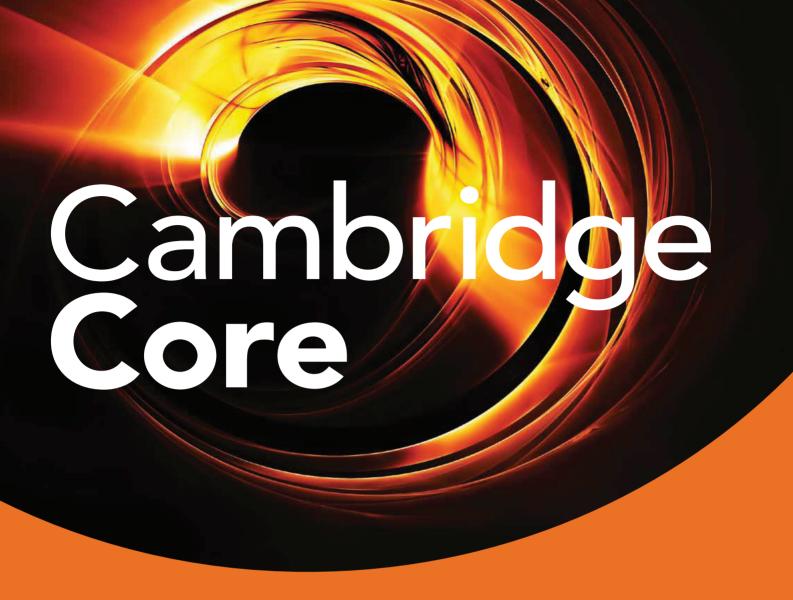


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71168-11	Bent Cryo Tong	each
71168-12	Shelved Puck Shipping Cane	each
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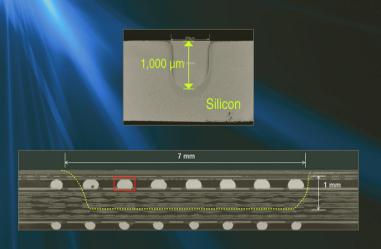
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